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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/064,302	07/01/2002	Matthew J. Breitwisch	BUR920010139	6396

28211 7590 04/23/2003

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EXAMINER

AUDUONG, GENE NGHIA

ART UNIT PAPER NUMBER

2818

DATE MAILED: 04/23/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

# Office Action Summary

Application No.

10/064,302

Applicant(s)

BREITWISCH ET AL.

Examiner

Gene N Auduong

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2818

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

## Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

## Status

- 1) ☐ Responsive to communication(s) filed on \_\_\_\_.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

## Disposition of Claims

- 4) ☒ Claim(s) 1-18 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_ is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1-18 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_ are subject to restriction and/or election requirement.

## Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on \_\_\_\_ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
- Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- 11) ☐ The proposed drawing correction filed on \_\_\_\_ is: a) ☐ approved b) ☐ disapproved by the Examiner.
- If approved, corrected drawings are required in reply to this Office action.
- 12) ☐ The oath or declaration is objected to by the Examiner.

## Priority under 35 U.S.C. §§ 119 and 120

- 13) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some \* c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- \* See the attached detailed Office action for a list of the certified copies not received.
- 14) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).
- a) ☐ The translation of the foreign language provisional application has been received.
- 15) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.

## Attachment(s)

- 1) ☒ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☒ Information Disclosure Statement(s) (PTO-1449) Paper No(s) 2.
- 4) ☐ Interview Summary (PTO-413) Paper No(s). \_\_\_\_.
- 5) ☐ Notice of Informal Patent Application (PTO-152)
- 6) ☐ Other: \_\_\_\_\_

## DETAILED ACTION

### *Information Disclosure Statement*

1. This office acknowledges receipt of the following items from the applicant:
  - Information Disclosure Statement (IDS), filed on July 1, 2002.

### *Claim Rejections - 35 USC § 102*

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

3. Claims 1-18 are rejected under 35 U.S.C. 102(b) as being anticipated by Chan et al. (U.S. Pat. No. 5,255,230).

Regarding claim 1, Chan et al. disclose an apparatus for testing SRAM comprising: an array of cells 10 (see abstract); and conductive lines connecting the cells together, wherein the conductive lines connect the cells together as if they were a single cell (figures 1-2, col. 3, lines 66+).

Regarding claim 2, Chan et al. disclose the apparatus for testing SRAM comprising all of the limitation as in claim 1, wherein the conductive lines comprise at least one of: a common word line; a common bit line; a common bit line complement line; a common N-well voltage line; a common interior ground line; a common interior voltage line; and a common ground line (figure 2, at least one common word line or bit line are connecting to the test pad, col. 4, lines 7+)

Regarding claim 3, Chan et al. disclose the apparatus for testing SRAM comprising all of the limitation in claim 1, wherein each of the conductive lines includes an individual test pad,

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wherein by connecting to each the test pad, the array can be tested for current leakage as if the array were an individual cell (figure 2, col. 4, lines 11+).

Regarding claim 4, Chan et al. disclose the apparatus for testing SRAM comprising all of the limitation in claim 2, further comprising at least one of: a word line contact pad connected to the common word line; a bit line contact pad connected to the common bit line; a bit line complement contact pad connected to the common bit line complement line; a voltage contact pad connected to the common N-well voltage line; an interior ground contact pad connected to the common interior ground line; an interior voltage contact pad connected to the common interior voltage line; and a ground line contact pad connected to the common ground line (figure 2, col. 4, lines 7+).

Regarding claim 5, Chan et al. disclose the apparatus for testing SRAM comprising all of the limitation in claim 1, wherein the array of cells comprises a plurality of memory cells, word lines, bit lines, voltage lines, and ground lines, and wherein the conductive lines: join all word lines within the array as a single word line; join all bit lines within the array as a single bitline; join all voltage lines within the array as a single voltage line; and join all ground lines together within the array as a single ground line (.see abstract, figures 1-2, col. 3, lines 66+).

Regarding claim 6, Chan et al. disclose the apparatus for testing SRAM comprising all of the limitation in claim 1, wherein applying a voltage to one conductive line of the conductive lines charges all elements connected to the conductive line within the array (col. 4, lines 7+).

Regarding claim 7, Chan et al. disclose the apparatus for testing SRAM comprising all of the limitation in claim 6, wherein measuring a current on one conductive line of the conductive lines measures an average current on all elements connected to the conductive line within the array (col. 4, lines 7+).

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Claims 8-13 contains the similar limitation as previously discussed in claims 1-7.

Therefore, they are analyzed as previously discussed with respect to claims 1-7.

Regarding claims 14-18, the apparatus as previously discussed in claims 1-7 and 8-13 would be performed the method as claimed. Therefore, they are analyzed as previously discussed with respect to apparatus claims 1-7 and 8-13.

*Conclusion*

4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Farnworth et al. (U.S. Pat. No. 5,898,186)

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Gene N Auduong whose telephone number is (703) 305-1343.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached on (703) 308-4910. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 872-9318 for regular communications and (703) 872-9319 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

GA  
April 18, 2003



Gene N Auduong  
Examiner  
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